

## Multiple-valued logic-in-memory VLSI based on a floating-gate-MOS pass-transistor network

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**FP 12.5: Multiple-Valued Logic-in-Memory VLSI  
Based on a Floating-Gate-MOS  
Pass-Transistor Network**

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A logic-in-memory structure, in which storage functions are distributed over a logic-circuit plane, is a solution to the communication bottleneck between memory and logic modules, one of the most serious problems in recent deep submicron VLSI systems. This logic-in-memory VLSI based on floating-gate MOS transistors merges storage and switching functions in a multiple-valued-input and binary-output combinational logic circuit that is useful for the realization of parallel arithmetic and logic circuits. Figure 1 shows a general structure of a 4-valued-input and binary-output combinational logic circuit. It has two kinds of inputs, external and stored constant inputs. In the logic-in-memory VLSI, a large number of stored data are distributed in not only word-parallel but also in digit-parallel manners.

Figure 2 shows a 4-valued-input binary-output pass-transistor network based on floating-gate MOS transistors. Four basic operations such as AND (serial connection of pass transistors), OR (parallel connection of pass transistors), a threshold literal (TL) and logic-value conversion (LVC) are used to represent arbitrary switching functions where these operations are defined in Figure 2a. Multiple-valued stored data are represented by the threshold voltage of a floating-gate MOS transistor, so that both multiple-valued threshold-literal and pass-switch functions can be merged by using a single floating-gate MOS transistor as shown in Figure 2b. Consequently, a compact pass-transistor network can be designed by using floating-gate MOS transistors as shown in Figure 2c.

A fully-parallel magnitude comparator between 4-valued external and stored data is a typical application of the logic-in-memory VLSI. Figure 3a shows the definition of TLs,  $g_i$  and  $g_{e_j}$ . The TL and pass-switch functions are merged in a pass-transistor network where the merged pass switch is defined as shown in Figure 3b. Since 4-valued stored data are represented by the threshold voltage of the floating-gate MOS transistor, memory is by storing 4-level charge on the floating gate of the transistor. As a result, a pass switch with a 4-valued TL function uses only a single floating-gate MOS transistor where 4-valued external-input and stored constant-input data are represented by a gate voltage and a threshold voltage as shown in Table 1.

Figure 4a shows a magnitude comparison between 4-valued 3-digit words,  $(s_1 s_2 s_3)$  and  $(b_1 b_2 b_3)$ , given by radix-4 number representation. According to the definition of a 4-valued pass switch shown in Figure 3c, a pass-transistor network for the magnitude comparison can be designed as shown in Figures 4b and 4c. To perform the pass-switch operation, the precharge-control and evaluate-control transistors are added as shown in Figure 4c. Two kinds of pass-switch operations for each input digit are realized by two different floating-gate MOS transistors, so that a general structure in case of  $n$ -digit word length can be designed by  $(2n+1)$  transistors as shown in Figure 4d.

Figure 5 shows layout and circuit diagrams of the pass-transistor network with 4 floating-gate MOS transistors in a 0.8 $\mu$ m double-metal double-polysilicon EEPROM technology. Although the pass-transistor network is constructed by the mixture of

serial and parallel connections of floating-gate MOS transistors, there is no hardware overhead in terms of interconnection area. Figure 6 shows a layout of the proposed logic-in-memory VLSI chip for 4-valued 16-digit magnitude comparison under the same process technology. Features are summarized in Table 2.

Table 3 shows the PSPICE simulation of the proposed logic-in-memory using a standard 0.8 $\mu$ m EEPROM technology. The number of execution steps is greatly reduced in the proposed logic-in-memory VLSI by the pass-transistor network, because highly parallel logic operations and storage functions are merged in the pass-transistor network. As a result, the execution speed of the proposed logic-in-memory VLSI is about 26 times and 6 times higher than those of both binary-CAM-based and conventional multiple-valued CAM-based implementations, respectively [2, 3]. The advantage of the number of execution steps also reduces power dissipation of the proposed logic-in-memory in comparison with that of other implementations because its precharge is only once for each execution cycle. Power dissipation of the logic-in-memory VLSI is reduced to about 21% and 24% of those of a binary CAM-based and conventional multiple-valued CAM-based implementations, respectively. The use of a floating-gate MOS transistor makes the area penalty of the pass-transistor circuit smaller.

*References:*

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- [2] Yamagata, T., et al., "A 288-kb Fully Parallel Content Addressable Memory Using a Stacked-Capacitor Cell Structure," IEEE J.Solid-State Circuits, SC-27, 12, pp.1927-1933, Dec., 1992.
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Logic value of input data	0	1	2	3	4
Gate voltage $V_x$	0.00V	1.25V	2.50V	3.75V	5.00V

Logic value of stored data	0	1	2	3
Threshold voltage $V_t$	0.63V	1.88V	3.13V	4.38V

**Table 1: Voltages corresponding to 4-valued logic levels.**

Technology	0.8- $\mu$ m EEPROM double-metal double-polysilicon
Number of words	32,768-word
Capacity	1Mb
Chip size	50mm <sup>2</sup>
Power supply voltage	5 V
Execution time	50ns

**Table 2: Features of a 4-valued logic-in-memory VLSI chip.**

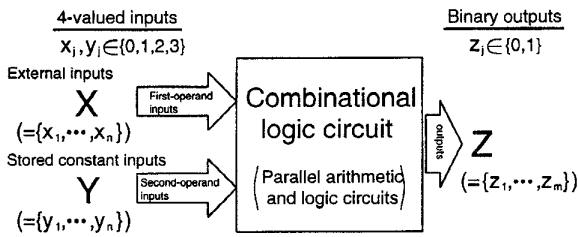
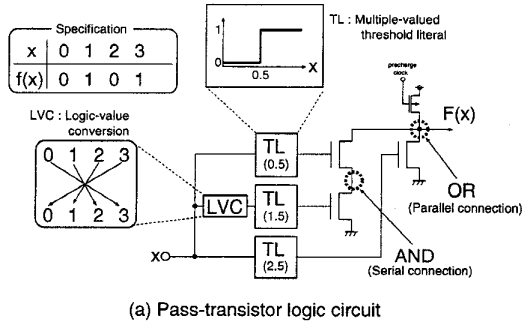


Figure 1: General structure.



(a) Pass-transistor logic circuit

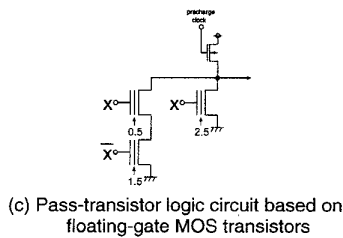
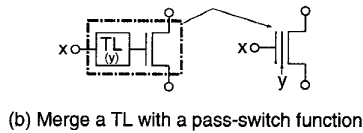


Figure 2: Design example.

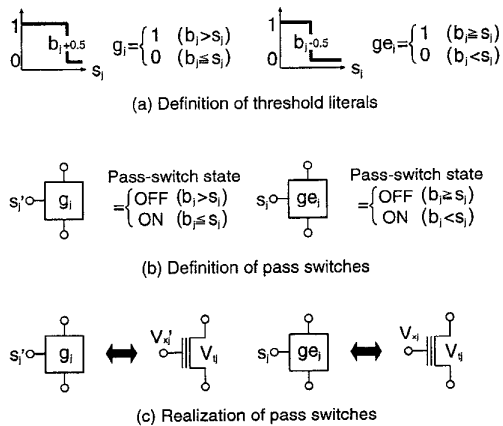
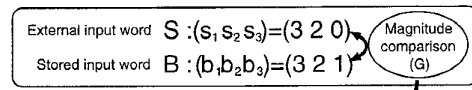


Figure 3: Floating-gate-MOS pass-transistor.



$$G = g_1 + ge_1 \cdot g_2 + ge_1 \cdot ge_2 \cdot g_3$$

$$= 1 \rightarrow B > S \text{ ('B' is greater than 'S')}$$

(a) Example of 4-valued 3-digit magnitude comparison

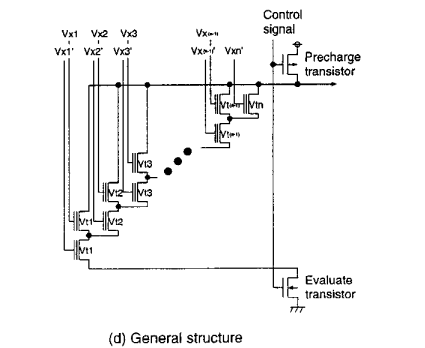
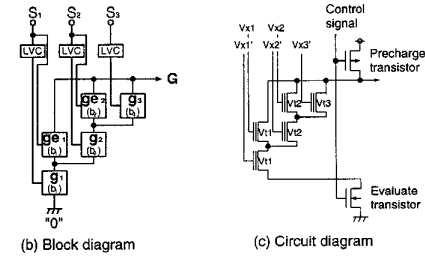


Figure 4: Magnitude comparator word circuit.

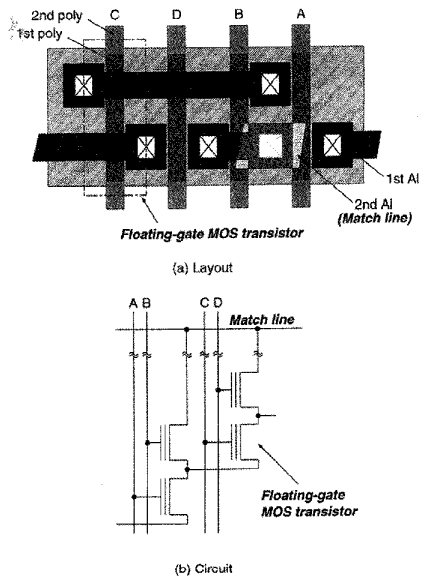


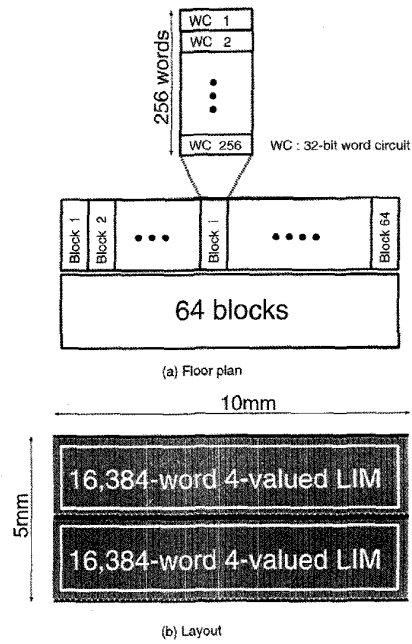
Figure 5: Floating-gate-MOS pass-transistor network.

Table 3 and Figure 6: See page 437.

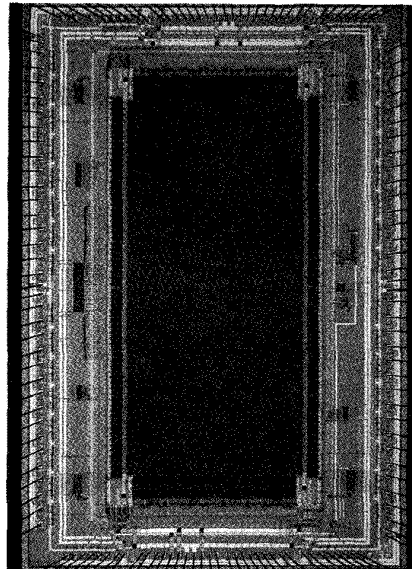
	Binary CAM	4-valued implementation	
		CAM	Proposed
Area/2bit	132 $\mu\text{m}^2$	21 $\mu\text{m}^2$	56 $\mu\text{m}^2$
Processing time /step	40nsec	20nsec	50nsec
No. of Execution steps	32	16	1
Execution time	1280nsec	320nsec	50nsec
Power dissipation /word	0.86mW	0.75mW	0.18mW

(PSPICE simulation based on a 0.8- $\mu\text{m}$  EEPROM technology)

**Table 3: Comparison of performances (32b 256 words).**



**Figure 6: 4-valued logic-in-memory (LIM) VLSI chip.**



**Figure 1: Chip micrograph.**